
Up-screening / Electrical Testing Capabilities – RF/ Mixed Signal/Digital

Advantest 93K (Present configuration)

- 640 pins **SmartScale**, with 128 channels of PS9G (32 with 8Gbps max), 24 RF ports, 512 PS1600 channels (128 with 1600Mbps); 112 Meg Vector depth, 4xMSDPS 8ch each, 1 MBAV8+, 1xDPS32
- 640 pins **SmartScale**, with 128 channels of PS9G (32 with 8Gbps max), 24 RF ports, 512 PS1600 channels (128 with 1600Mbps); 112 Meg Vector depth, 4xMSDPS 8ch each, 1 MBAV8+, 1xDPS32
- 832 pins **Pin Scale**, with full analog option, 32Meg Vector depth, 64 PS3600 channels fully enabled, 4xMSDPS 8ch ea, 1 HCDPS 1ch, 1xUHCC4 4ch at 40A ea, 12 TIA ea on PS800 and PS3600 pins
- 800 pins **Pin Scale**, with full analog option, 64Meg Vector depth, 64 PS3600 channels fully enabled, 4xMSDPS 8ch ea, 1xUHCC4 4ch at 40A ea, 1xMBAV8, 2 – HXA cards 2 lanes each @12.5Gbps
- 608 pins **Pin Scale**, with full analog option, 64Meg Vector depth, with 32pins of PS3600 4xMSDPS 8ch ea, 1xDPS32, 12 TIA ea on PS800 and PS3600 pins
- 864 pins **93K SOC**, P1000,with full analog option, 4xGPDPS 4ch ea, up to 112Meg vector depth
- 832 pins **93K SOC**, P1000,with full analog option, 4xGPDPS 4ch ea, 1xHCDPS 1ch at 100A, up to 112Meg vector depth

Credence (Present configuration)

- Quartet, mixed signal test system, analog option and 448 I/O, 200 MHz, 64 Meg Vector depth, with 128 Meg scan memory
- SC312 Credence, 304 tester Channels, Mixed Signal Tester – Total of 3 testers
- SC212 Credence, 304 tester Channels, Mixed Signal Tester – Total of 1 testers
- LTX Fusion CX, 64 Tester Channels, Mixed Signal and RF Tester, 8 RF channels
- LTX Credence ASLX, 118 Tester Channels Mixed Signal Tester
- LTX Credence ASL1000, 74 Tester Channels Mixed Signal Tester
- LTX Credence D10, 576 pins, Digital and Memory Tester

Sentry

- Sentry 21; 60 pin; Up to 20MHz; Low Voltage/High Voltage Test Heads; Up to 16 Timing Generators/156 pS resolution; Maximum Current = +/- 100mA; Resolution = +/- 1nA; Pin Electronics = +6V/-2V (High Speed)/+6/-22V(High Voltage); Precision Measurement Unit = +/- 100V

Wafer Probers

Model No.	Manufacturer	Description
UF3000 EX	TSK	Wafer Prober – 12” – with Cold Chuck -45C to +125C capability
UF3000 EX	TSK	Wafer Prober – 12” 25C to +125C capability
UF200	TSK	Wafer Prober – 8” 25C to +125C capability

Test Handlers

Model No.	Manufacturer	Description
NS-8040 (qty 2)	Epson	Quad Site with Peltier Active Temperature Control (ATC) 25C to +125C capability
SC3100 (qty 2)	Synax	Quad Site 25C to +125C capability
SC1211 (qty 2)	Synax	Dual Site 25C to +125C capability